



## DYNAMIC ENGINEERING

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# Statement of Volatility

## PN: PC104p-BiSerial-VI

**Manufacturer Part Number:** PC104p-BiSerial-VI, includes all types (-UART, etc.)

**Manufacturer Part Description:** PCI-104, PC104p with FPGA, FIFO options, RS485 and LVDS options, IO, PLL

**Memory Type:** FLASH, SRAM, FIFO

**Memory Size:** varies with installed FPGA and FIFOs

**Volatility:** SRAM and FIFO memories cleared by power cycle. FLASH is retained through power cycle. FLASH is not accessible by user for writing or read-back. FLASH is used to reload FPGA at power-on.

**User Accessible:** SRAM within FPGA is configured into registers etc. FPGA features are R/W [in many cases] to user software. SRAM contents are lost at power down and re-written with base design from FLASH upon power-on. External FIFOs are used to store user data during operation. All data is lost when powered down. When reset, pointers are reset making current data inaccessible. Some models do not have external FIFOs.

**Clearing Procedure:** Power cycle or re-write data stored contents per approved procedure. SRAM model for internal and FIFO.

**Notes or Warnings:** None